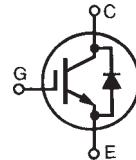


**Polar™ IGBT****IXGQ 100N60PBD1**
 $V_{CES}$   
 $I_{C25}$ 

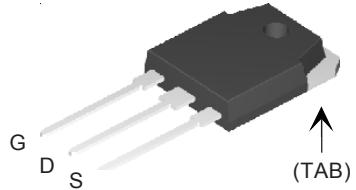
= 600 V  
= 100 A

**With Anti-Parallel Diode  
For PDP Applications**


Symbol	Test Conditions	Maximum Ratings	
$V_{CES}$	$T_J = 25^\circ\text{C}$ to $150^\circ\text{C}$	600	V
$V_{GES}$	Continuous	$\pm 20$	V
$V_{GEM}$	Transient	$\pm 30$	V
$I_{C25}$	$T_c = 25^\circ\text{C}$ , IGBT chip capability	100	A
$I_{C90}$	$T_c = 90^\circ\text{C}$	75	A
$I_{CM}$	$T_J \leq 150^\circ\text{C}$ , $t_p < 300 \mu\text{s}$	188	A
$I_{C(\text{RMS})}$	Lead current limit	75	A
<b>SSOA</b> <b>(RBSOA)</b>	$V_{GE} = 15 \text{ V}$ , $T_{VJ} = 150^\circ\text{C}$ , $R_G = 20 \Omega$ Clamped inductive load, $V_{CE} < 600 \text{ V}$	$I_{CM} = 100$	A
$P_c$	$T_c = 25^\circ\text{C}$	340	W
$T_J$		-55 ... +150	$^\circ\text{C}$
$T_{JM}$		150	$^\circ\text{C}$
$T_{stg}$		-55 ... +150	$^\circ\text{C}$
Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	$^\circ\text{C}$
$M_d$	Mounting torque	1.3/10 Nm/lb.in.	
<b>Weight</b>	TO-247	6.0	
	g		

Symbol	Test Conditions ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
$V_{GE(\text{th})}$	$I_c = 250 \mu\text{A}$ , $V_{CE} = V_{GE}$	2.5		5.0 V
$I_{CES}$	$V_{CE} = V_{CES}$ $V_{GE} = 0 \text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		1 $\mu\text{A}$ 200 $\mu\text{A}$
$I_{GES}$	$V_{CE} = 0 \text{ V}$ , $V_{GE} = \pm 20 \text{ V}$			$\pm 100$ nA
$V_{CE(\text{sat})}$	$V_{GE} = 15 \text{ V}$ , $I_c = 50 \text{ A}$ $I_c = 100 \text{ A}$	$T_J = 125^\circ\text{C}$	1.30 1.31 1.63 1.77	1.50 V V 1.80 V V

TO-3P (IXTQ)

**Features**

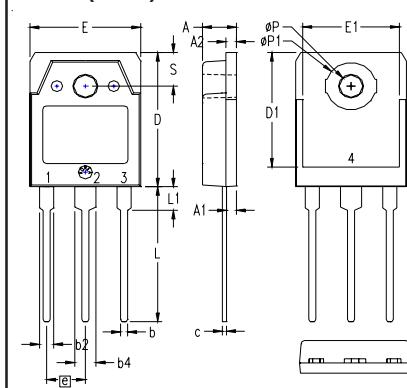
- International standard package
- Low  $V_{CE(\text{sat})}$ 
  - for minimum on-state conduction losses
- MOS Gate turn-on
  - drive simplicity

**Applications**

- PDP Screen Drivers
- AC motor speed control
- DC servo and robot drives
- DC choppers
- Uninterruptible power supplies (UPS)
- Switch-mode and resonant-mode power supplies
- Capacitor discharge

Symbol	Test Conditions	Characteristic Values		
	( $T_J = 25^\circ\text{C}$ , unless otherwise specified)	Min.	Typ.	Max.
$g_{fs}$	$I_C = 50 \text{ A}$ , $V_{CE} = 10 \text{ V}$ Pulse test, $t \leq 300 \mu\text{s}$ , duty cycle $\leq 2\%$	32	48	S
$C_{ies}$	$V_{CE} = 25 \text{ V}$ , $V_{GE} = 0 \text{ V}$ , $f = 1 \text{ MHz}$	2500	pF	
$C_{oes}$		190	pF	
$C_{res}$		69	pF	
$Q_g$	$I_C = 50 \text{ A}$ , $V_{GE} = 15 \text{ V}$ , $V_{CE} = 0.5 V_{CES}$	160	nC	
$Q_{ge}$		24	nC	
$Q_{gc}$		93	nC	
$t_{d(on)}$	<b>Resistive load, <math>T_J = 25^\circ\text{C}</math></b>	45	ns	
$t_{ri}$		142	ns	
$t_{d(off)}$		147	ns	
$t_{fi}$		217	ns	
$t_{d(on)}$	<b>Inductive load, <math>T_J = 125^\circ\text{C}</math></b>	41	ns	
$t_{ri}$		148	ns	
$t_{d(off)}$		153	ns	
$t_{fi}$		363	ns	
$R_{thJC}$			0.37	K/W
$R_{thCK}$			0.25	K/W

## TO-3P (IXTQ) Outline



1 - GATE  
2 - DRAIN (COLLECTOR)  
3 - SOURCE (EMITTER)  
4 - DRAIN (COLLECTOR)

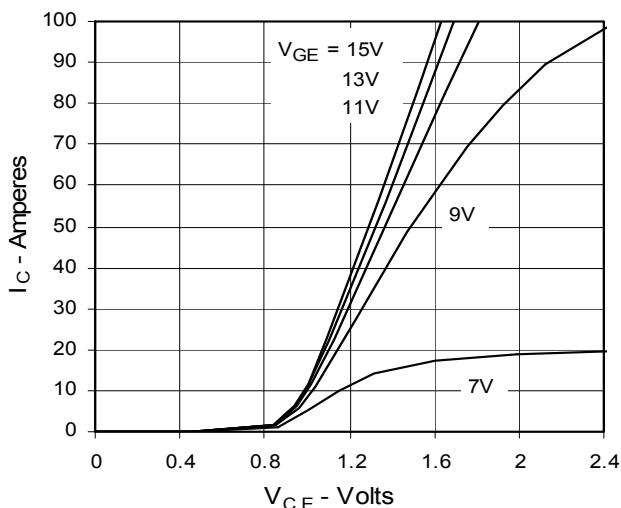
SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.193	4.70	4.90
A1	.051	.059	1.30	1.50
A2	.057	.065	1.45	1.65
b	.035	.045	0.90	1.15
b2	.075	.087	1.90	2.20
b4	.114	.126	2.90	3.20
c	.022	.031	0.55	0.80
D	.780	.791	19.80	20.10
D1	.665	.677	16.90	17.20
E	.610	.622	15.50	15.80
E1	.531	.539	13.50	13.70
e	.215 BSC		5.45 BSC	
L	.779	.795	19.80	20.20
L1	.134	.142	3.40	3.60
$\varnothing P$	.126	.134	3.20	3.40
$\varnothing P1$	.272	.280	6.90	7.10
S	.193	.201	4.90	5.10

All metal areas are tin plated.

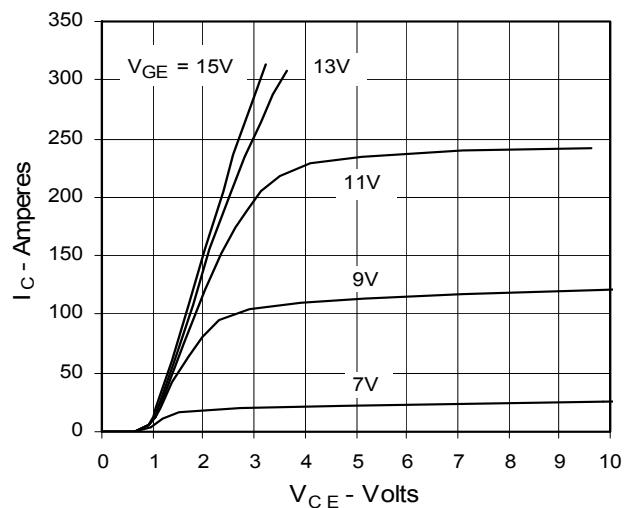
## Reverse Diode

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
$V_F$	$I_F = 20 \text{ A}$ , $V_{GE} = 0 \text{ V}$		2.0	V
$R_{thJC}$			2.5	K/W

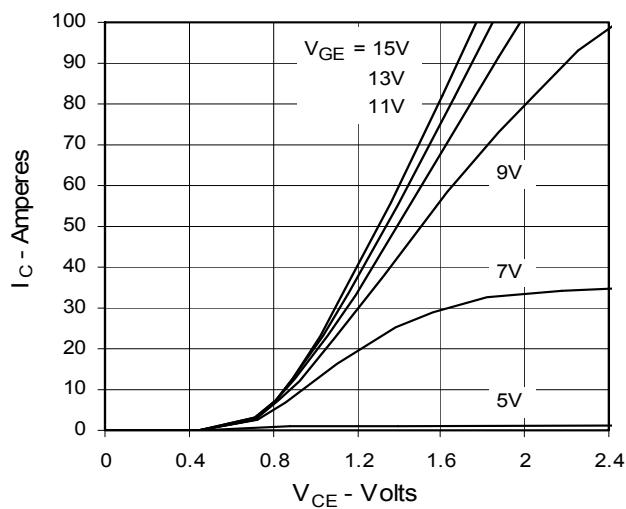
**Fig. 1. Output Characteristics  
@ 25 °C**



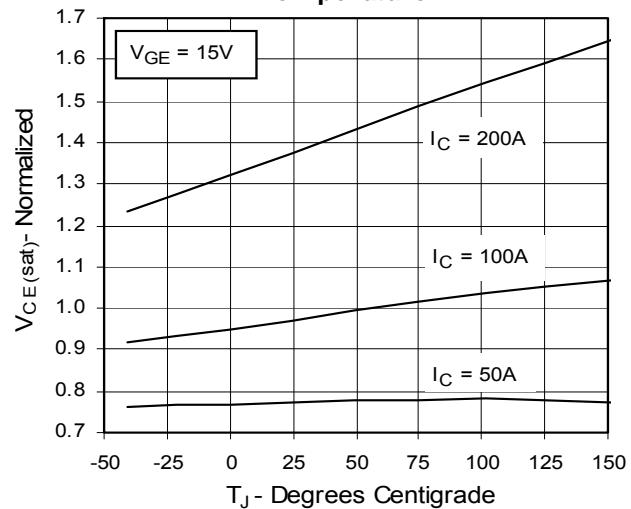
**Fig. 2. Extended Output Characteristics  
@ 25 °C**



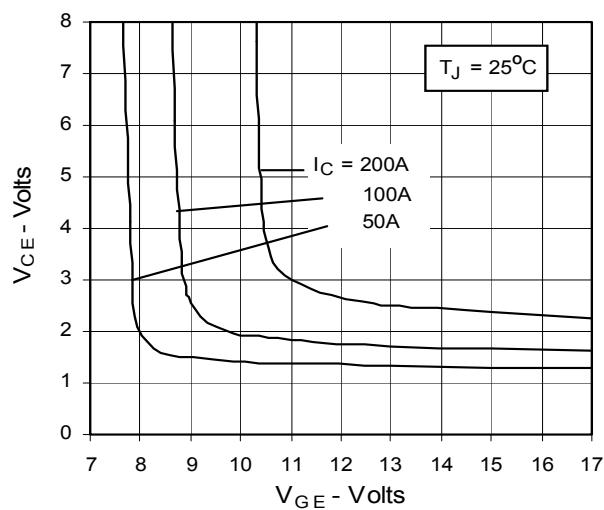
**Fig. 3. Output Characteristics  
@ 125 °C**



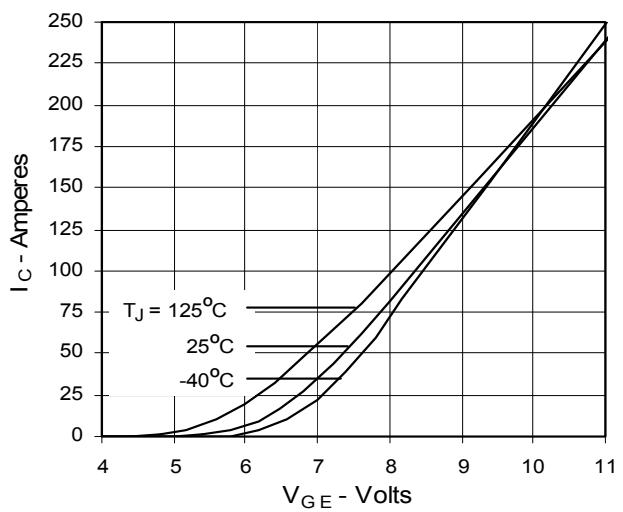
**Fig. 4. Dependence of  $V_{CE(sat)}$  on Temperature**

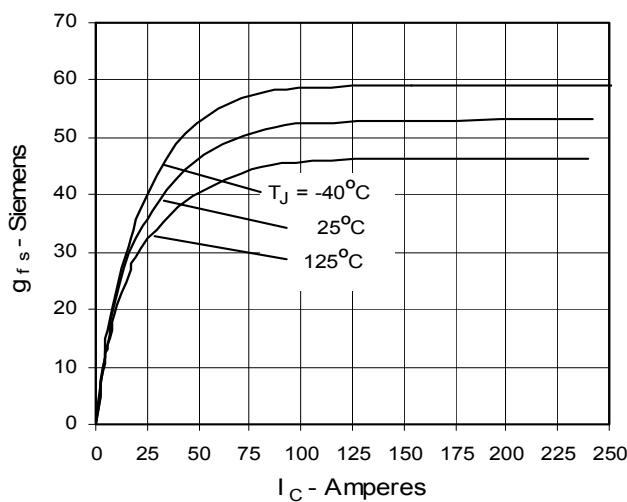
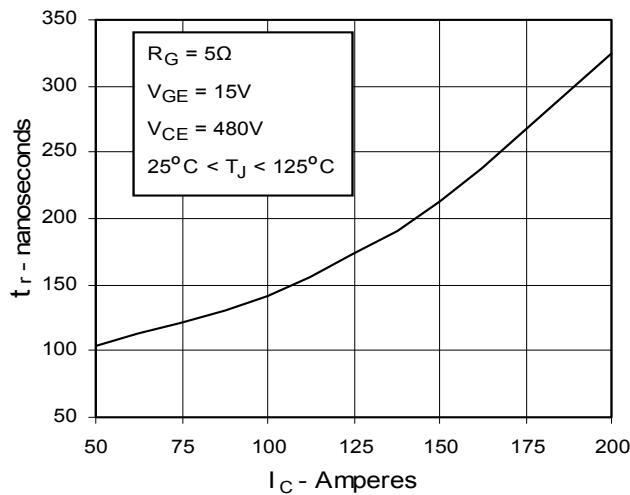
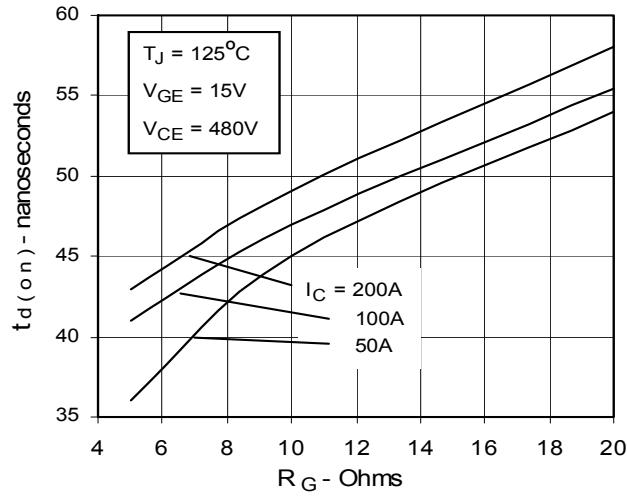
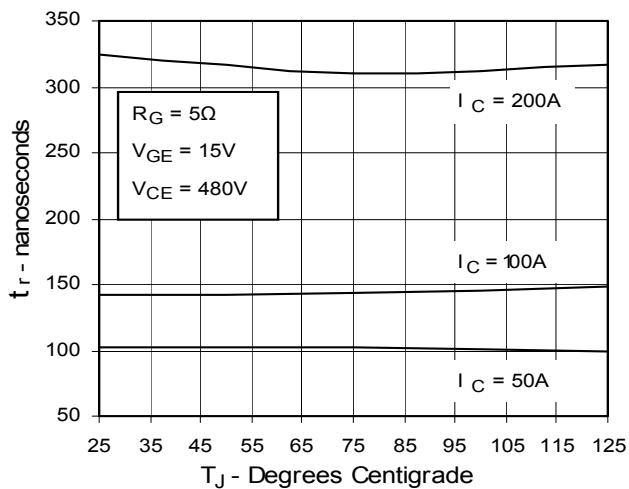
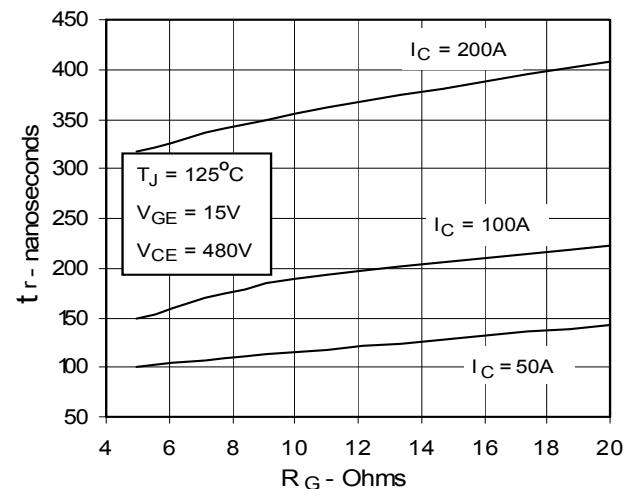
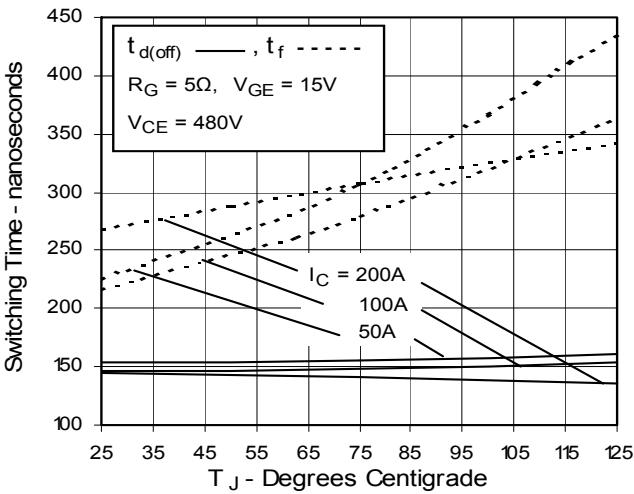


**Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter voltage**

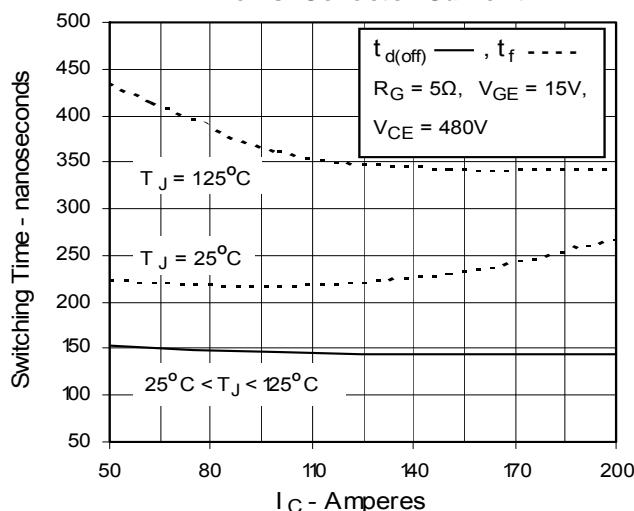


**Fig. 6. Input Admittance**

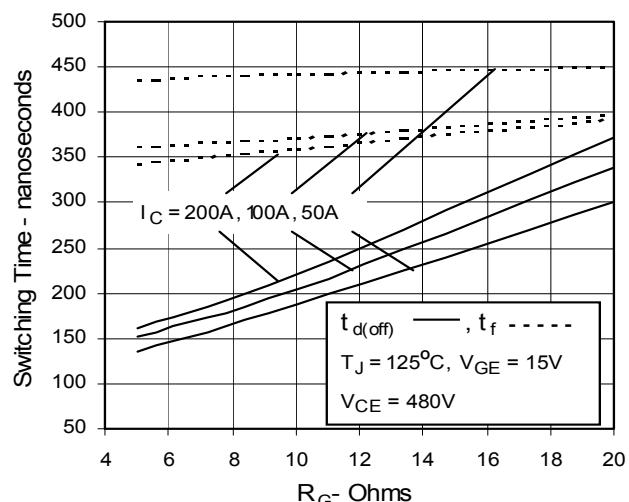


**Fig. 7. Transconductance**

**Fig. 9. Resistive Turn-On Rise Time vs. Collector Current**

**Fig. 11. Resistive Turn-On Delay Time vs. Gate Resistance**

**Fig. 8. Resistive Turn-On Rise Time vs. Junction Temperature**

**Fig. 10. Resistive Turn-On Rise Time vs. Gate Resistance**

**Fig. 12. Resistive Turn-Off Switching Time vs. Junction Temperature**


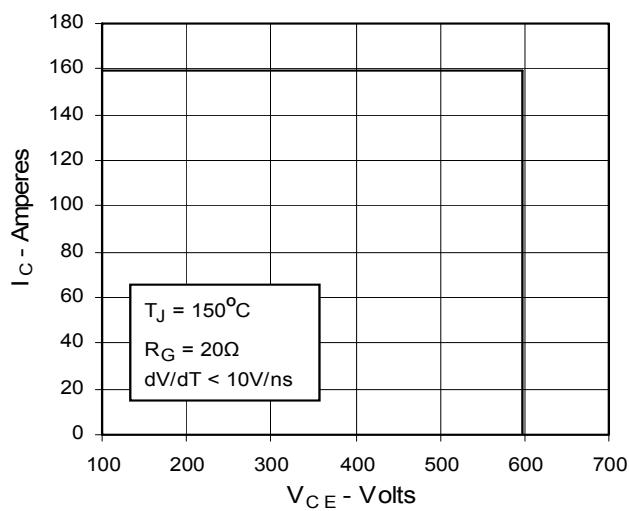
**Fig. 13. Resistive Turn-Off Switching Time vs. Collector Current**



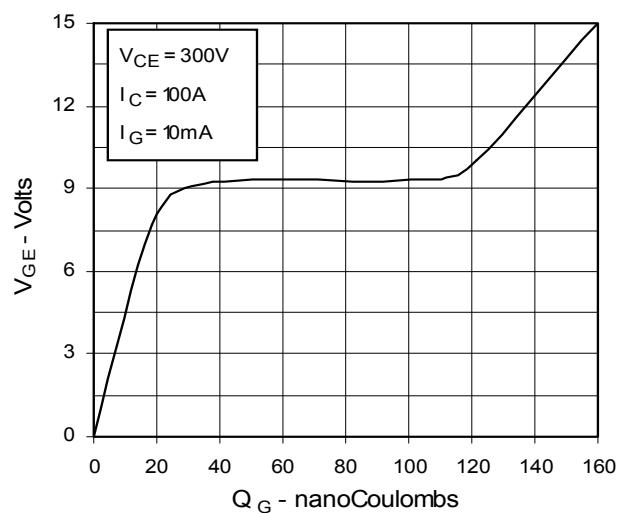
**Fig. 14. Resistive Turn-off Switching Time vs. Gate Resistance**



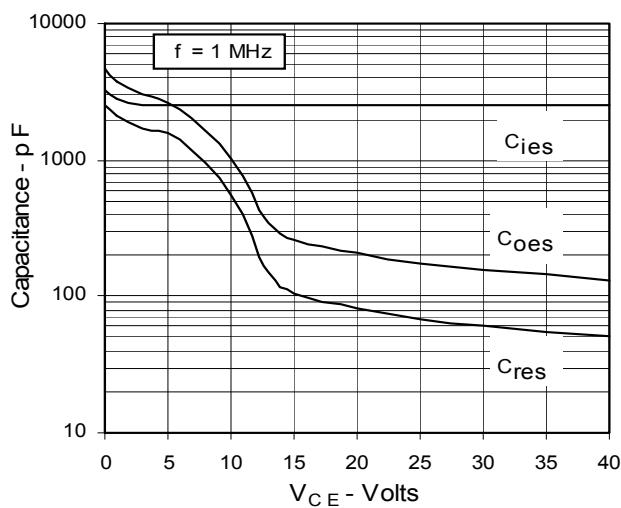
**Fig. 15. Reverse-Bias Safe Operating Area**



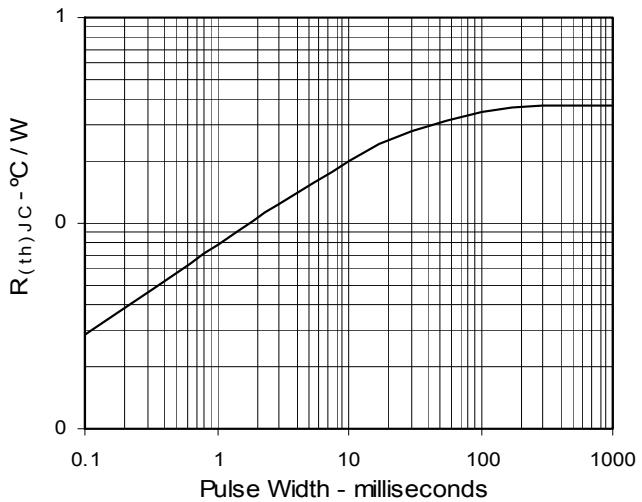
**Fig. 16. Gate Charge**

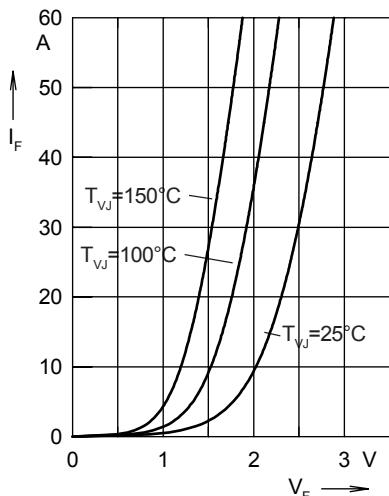


**Fig. 17. Capacitance**

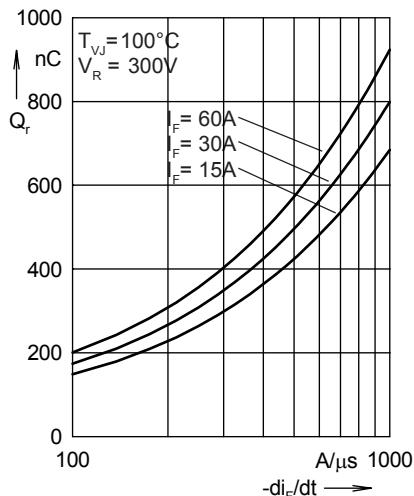


**Fig. 18. Maximum Transient Thermal Resistance**

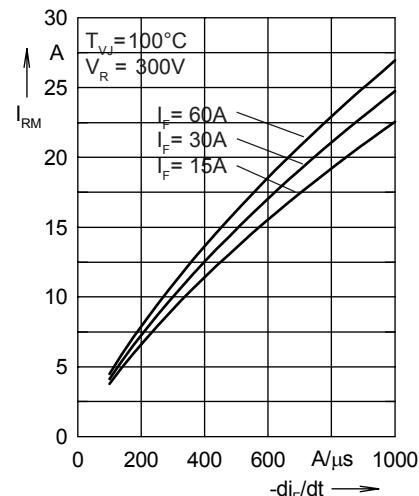




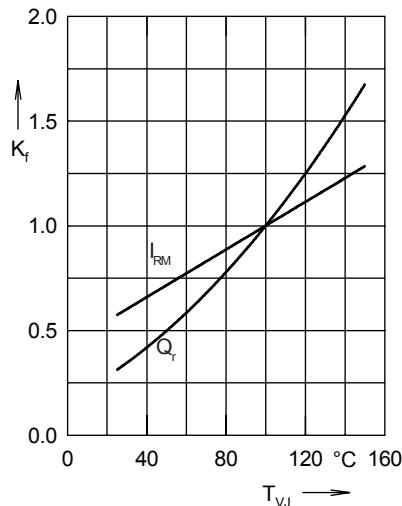
**Fig.19. Forward current  $I_F$  versus  $V_F$**



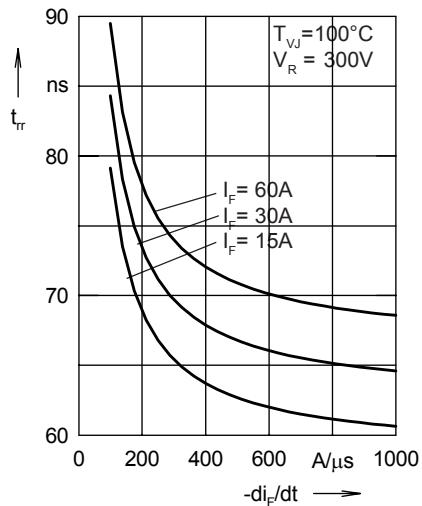
**Fig.20. Reverse recovery charge  $Q_r$  versus  $-di_F/dt$**



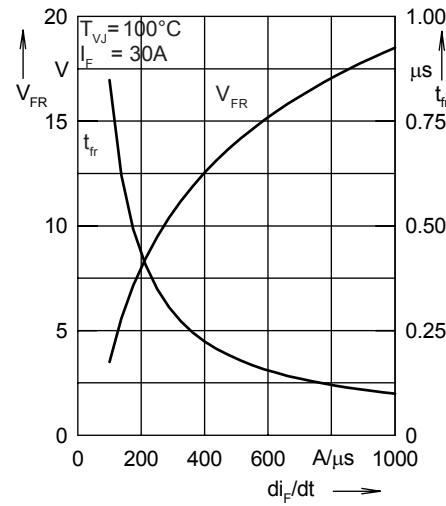
**Fig.21. Peak reverse current  $I_{RM}$  versus  $-di_F/dt$**



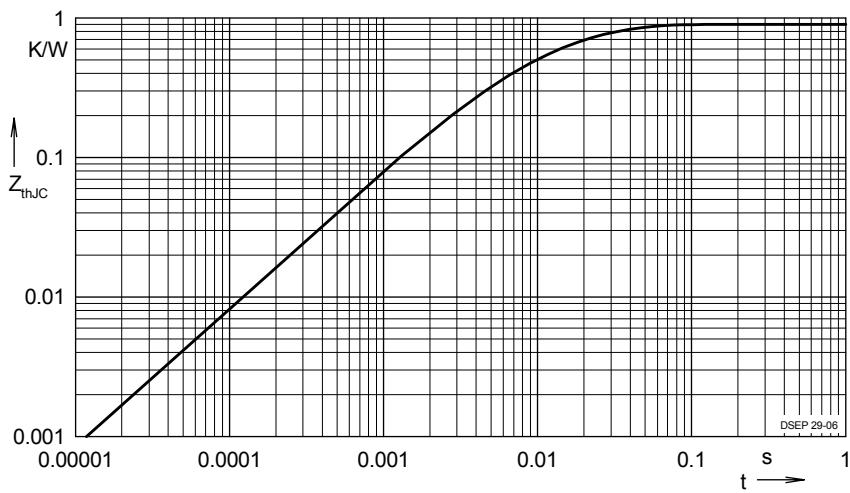
**Fig.22. Dynamic parameters  $Q_r$ ,  $I_{RM}$  versus  $T_{VJ}$**



**Fig.23. Recovery time  $t_{rr}$  versus  $-di_F/dt$**



**Fig.24. Peak forward voltage  $V_{FR}$  and  $t_{tr}$  versus  $di_F/dt$**



**Fig.25. Transient thermal resistance junction to case**

Constants for  $Z_{thJC}$  calculation:

i	$R_{thi}$ (K/W)	$t_i$ (s)
1	0.502	0.0052
2	0.193	0.0003
3	0.205	0.0162